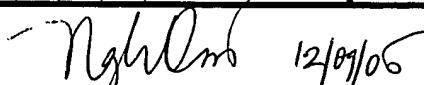


<b>Issue Classification</b>		Application/Control No.	Applicant(s)/Patent under Reexamination	
		10/751,629	KWAK ET AL.	
		Examiner	Art Unit	
		David Q. Nguyen	2617	

ORIGINAL				CROSS REFERENCE(S)					
CLASS	SUBCLASS	CLASS		SUBCLASS (ONE SUBCLASS PER BLOCK)					
455	452.2	455	446	442	435.3	436	407	456.2	
INTERNATIONAL CLASSIFICATION			370	329					
H	0	4	Q	7/20					
				/					
				/					
				/					
				/					
 (Assistant Examiner) (Date)				 <b>JOSEPH FEILD</b> <b>SUPERVISORY PATENT EXAMINER</b> (Primary Examiner) (Date)				Total Claims Allowed: 5	
(Legal Instruments Examiner) (Date)								O.G. Print Claim(s) 1	C.C. Print 7

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
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30		60	90	120	150	180	210